

National Updates

Proposed Changes to the Select Agent and Toxin List

On August 28, 2007, USDA-APHIS issued a public notice concerning proposed changes to the select agent and toxin list.

Specific proposed changes and additions to the select agent and toxin list that pertains to plant pathogens include:

- The removal of *Candidatus Liberobacter asiaticus*, the causative agent of citrus greening.
- The regulation of all pathovars of *Xanthomonas oryzae*, the causative agent of bacterial leaf streak.
- The addition of *Candidatus Liberobacter americanus*. This pathogen is also a causative agent of citrus greening disease but has

only been reported in San Paulo State, Brazil.

- The addition of *Phoma glycinicola*, the causative agent of red blotch of soybean.
- The addition of *Phytophthora*

kernoviae which is similar to *P. ramorum* but more aggressive.

- The addition of *Rathayibacter toxicus*, the causative agent of gumming of ryegrass.

These proposed changes are open for comment through **October 29, 2007**.

The complete Federal Register posting as well as instructions on how to make comments can be accessed at <http://www.regulations.gov/fdmspublic/component/main>.



Symptoms of *P. kernoviae* infection on an azalea (Photo Paul Beales, Central Science Laboratory, www.forestryimages.org)

Issue Highlights:

- ◆ Proposed Changes to the Select Agent and Toxin List
- ◆ 2007 National Soybean Rust Symposium Announcement
- ◆ Recent Detections of Rice Panicle Mite in the U.S.
- ◆ Diagnostic Tip of the Month: Diagnostic Uses for the Inverted Microscope
- ◆ Announcement for Mycotoxin Virtual Workshop Via Adobe Connect, November 6-8, 2007
- ◆ 4th Annual IT/Diagnostician's Meeting Announcement with List of Regional Representatives
- ◆ Sirex Woodwasp Detected in Vermont

National Updates

2007 National Soybean Rust Symposium To Be Held December 14-16, Louisville, KY

Now in its third consecutive year, APS is pleased to announce the 2007 National Soybean Rust Symposium.

The symposium will examine soybean rust from virtually every angle. In addition to opportunities to network and explore new areas of investigation, there will be presentations and discussions on molecular biology and genetics, development of disease resistant varieties, use of fungicides, disease management strategies and tactics, computer simulations, experiences and perceptions of producers and crop consultants, and much more. For more information including program details and registration, please visit the [2007 National Soybean Rust Symposium web site](#).

Recent Detections of Panicle Rice Mite in Rice Research Facilities

Over the past three months there have been four detections of the Panicle Rice Mite (PRM) within the continental United States and one detection in a U.S. territory. These detections were made in rice research facilities in Texas (July 13), Puerto Rico (August 1), Louisiana (August 20), Arkansas (September 7) and New York (September 14).

PRM is considered a serious rice pest and can cause substantial crop losses. There are two main reported hosts of the panicle rice mite, rice, *Oryza sativa*, and the weedy red rice, *Oryza latifolia*.

For more information on these detections, please visit on the web the following links:

[Detections of Panicle Rice Mite, *Steneotarsonemus spinki*, in Stuttgart, Arkansas and Ithaca, New York – United States](#)

[Detections of Panicle Rice Mite, *Steneotarsonemus spinki*, in Rayne, Acadia Parish, Louisiana - United States](#)

[Detections of Panicle Rice Mite, *Steneotarsonemus spinki*, in Lajas, Puerto Rico](#)

[Detections of Panicle Rice Mite, *Steneotarsonemus spinki*, in Brazoria County, Texas - United States](#)



Rice, *Oryza sativa* L. One of the hosts for the Panicle Rice Mite. (Photo David Nance, USDA-ARS, www.ipmimages.org)

Diagnostic Tip of the Month: Diagnostic Uses for the Inverted Microscope

Jan Byrne
Cassandra Bates
Angie Tenney
Michigan State
University

An inverted microscope is a helpful tool that can save diagnosticians time when looking at both nematology extraction samples and fungal cultures. An inverted microscope has a light source above the stage while the objectives are mounted on a nosepiece below the stage (Figure 1).

The stage is large enough to easily hold a petri dish. This design allows the diagnostician to easily scan cultures/samples without having to make a slide mount. A range of magnifications are available, inverted microscopes in our lab have the capability to magnify from 40x to 400x.

Fungal cultures can be viewed without opening the petri dish. The culture is placed on the stage and scanned for signs of fungal growth. This is a great way to find fungal structures that may not be widely prevalent in the culture or that were formed only directly adjacent to the plant material.

For example, it is really useful to detect *Phytophthora* sp. in cultures from woody plants where there is not a lot of fungal growth. Cultures can be quickly scanned

and if needed specific areas of the cultures can be marked for more detailed examination later on a



Figure 1. An inverted microscope has a light source above the stage while the objectives are mounted on a nosepiece below the stag. (Photo Jan Byrne, Michigan State University)

traditional compound microscope. In some cases scanning cultures with the inverted scope is sufficient to make a diagnosis, eliminating the need to make a slide mount. Because you don't have to disturb the culture, it is also a nice way to capture great images of structures.

The inverted microscope is also helpful in evaluating nematology samples; it is an efficient way to count cyst nematode samples. The extracted sample should be

poured into a 60mm x 15mm Petri dish. There is an attachment that fits on the stage of the microscope and holds a 60 mm Petri plate (Fig 2.). With the phase contrast on setting 3 and 40x magnification, the reader can readily differentiate between cysts and white females.

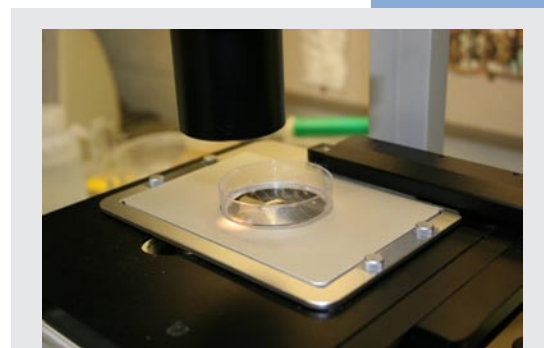


Figure 2. There is an attachment that fits on the stage of the microscope and holds a 60 mm Petri plate. (Photo Jan Byrne, Michigan State University)

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Diagnostic Tip of the Month

Diagnostic Update

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Vermiform nematodes can also be viewed and evaluated with the microscope. In this

instance, use no phase contrast and the light at a comfortable intensity. This will allow you to count the sample as if you were using a dissecting microscope. In order to view morphological characteristics, change your magnification as you would when looking at any other sample.

Mycotoxin Virtual Workshop Via Adobe Connect, November 6-8, 2007

You are invited to participate in a virtual workshop on “Mycotoxins and Mycotoxicosis” via Adobe Connect.

The workshop will be co-hosted by Nina Zidack (GPDN) and Gail Ruhl (NCPDN). Presenters for this workshop will be Dr. Barry Jacobsen (Montana State University) and Dr. Charles Woloshuk (Purdue University). The primary focus of the workshop will be to provide diagnosticians with sufficient background to determine if mycotoxin-producing fungi are present in a sample and if specific genera are observed, how and where to direct the sample to a lab for analytical testing.

The workshop will be delivered in 2 2hr sessions, November 6 and 8, mid-day (time to be announced later), so we may serve all time zones. In order to present this virtual workshop we will need a minimum of 10 confirmed participants (maximum 100).

Please share this announcement with colleagues who might be interested. Details on last year’s workshop and links to the recorded workshop are available at: <http://diagnostics.montana.edu/GPDN/Mycotoxin/index.htm>

To reserve a space in this upcoming E-workshop, please respond to ruhlg@purdue.edu and you will be added to our contact list of registrants.

National Database

4th Annual IT/Diagnostician’s Meeting

Mike Hill
CERIS Programmer/Analyst
Purdue University

The 4th annual IT/Diagnostician’s meeting will be held at the Adam’s Mark hotel in St. Louis, MO on November 28-29, 2007. Members of the PDIS change management team will meet for a half day on the afternoon of Tuesday November 27th. The IT/Diagnostician’s meeting will begin on Wednesday November 28th at 8:00am and conclude on Thursday November 29th at noon. PDIS users will meet for a half day in the afternoon on November 29th.

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Representatives from all regions consisting of three diagnosticians as well as IT staff have been invited to attend this meeting.

If you have specific input on National Repository uploads or about PDIS that you would like addressed at this meeting, please contact your regional representative below prior to the meeting so they can bring up your comments at the meeting.

GPDN Representatives:

Joy Pierzynski, Kansas State University, Diagnostic Representative
Will Lanier, Montana State University, Diagnostic Representative
Amy Ziems, University of Nebraska, Diagnostician Representative

Will Baldwin, Kansas State University, IT Representative
Jayasri Krishnasamy, Kansas State University, IT Representative

NCPDN Representatives:

Jan Byrne, Michigan State University, Diagnostic Representative
Simeon Wright, University of Missouri, Diagnostic Representative
Karen Rane, moving from Purdue University to the University of Maryland, Diagnostic Representative

Lee Duynslager, Michigan State University, IT Representative
Eileen Luke, Purdue University, IT Representative

Forrest Nutter, Iowa State University, Epidemiology Representative

NEPDN Representatives:

Karen Snover-Clift, Cornell University, Diagnostic Representative

Robert Durgy, University of Connecticut, Diagnostic Representative
Nancy Gregory, University of Delaware, Diagnostic Representative

Karen Scott, Cornell University, IT Representative
Julie Golod, IPM PIPE (Penn State), IT Representative

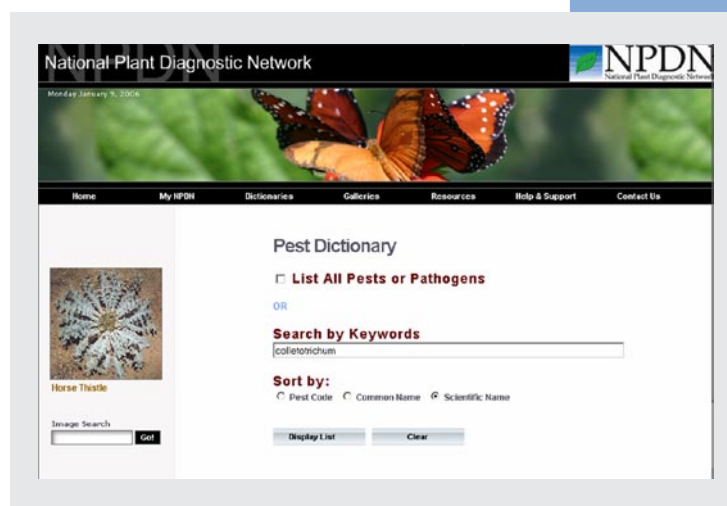
SPDN Representatives:

Ann Vitoreli, University of Florida, Diagnostic Representative
Nick Singh, Louisiana State University, Diagnostic Representative
Tom Creswell, North Carolina State University, Diagnostic Representative

David Barber, University of Georgia, IT Representative
Howard Beck, University of Florida, IT Representative

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National Database



Regional Updates

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Northeast Region

First Detection of Sirex Woodwasp, *Sirex noctilio* Fabricius, in Vermont

On September 5, 2007 the USDA-APHIS confirmed the detection of a single female sirex woodwasp (*Sirex noctilio*) in Lamoille, Vermont.

The insect was caught in a trap as part of a cooperative State and Federal survey effort. This is the first detection of this pest in New England. The sirex woodwasp is a highly significant, regulated pest that has the potential to cause widespread mortality to pine trees.

To date, sirex woodwasp has been detected in 28 counties in New York, 5 counties in Pennsylvania, 1 county in Michigan and 1 county in Vermont.

More information on this pest and this detection can be found on the web at:

[NAPPO Phytosanitary Alert System: Detection of *Sirex noctilio* Fabricius \(*Sirex* woodwasp\) in Lamoille County, Vermont – United States](#)

SPDN Representatives continued:

Alan Henn, Mississippi State University, IT

Representative
Ray Kimsey, North Carolina State University, IT Representative
Todd Powell, PCLinic (Virginia Tech), IT Representative

WPDN

Representatives:
Carla Thomas, UC Davis, Diagnostic Representative
Tim Tidwell, CDFA, Diagnostic Representative
Melodie Putnam, Oregon State University, Diagnostic Representative

Andrew Coggeshall, UC Davis, IT Representative
Casey Estep, California Dept. of Food and Agriculture, IT Representative

Leonard Coop, Oregon State University, Epidemiology

Meeting participants can make reservations at the Adam's Mark hotel by calling 1-800-444-2326 and mentioning "NPDN" as the meeting name. Please contact Mike Hill at 765-494-9854 if you have any questions about the upcoming meeting. We look forward to seeing you in St. Louis.



Adult sirex woodwasp. (Photo William Ciesla, Forest Health Management International, www.forestryimages.org)

National Events

November 28-29, 2007, [4th Annual IT/Diagnostician's Meeting](#), St. Louis, MO

December 9-12, 2007, [ESA Annual Meeting](#), San Diego, CA

December 12-14, 2007, [2007 National Soybean Rust Symposium](#), Louisville, KY

March 24-26, 2009, [Sixth International IPM Symposium](#), Portland, OR

Northeast Region

October 10-12, 2007, [Northeast Division APS Meeting](#), Cape May, NJ

February 26-28, 2008, NEPDN Regional Meeting, Chadds Ford, PA

Western Region

October 15-17, 2007, [Thrips Identification Workshop](#), Davis, CA

Upcoming Events



[Mary McKellar](#) Editor
NEPDN
Cornell University

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